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**Examiner**

PAUL T. CHIN

**Applicant(s)/Patent under  
Reexamination**

MATSUDA ET AL.

**Art Unit**

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**SEARCHED**

Class	Subclass	Date	Examiner
294	106	3/20/2009	PTC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR